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(54) **HIGH THROUGHPUT MECHANICAL PROPERTY TESTING OF MATERIALS LIBRARIES USING A PIEZOELECTRIC**

**Related U.S. Application Data**

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(57) **ABSTRACT**

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The present invention provides instruments and methods for screening combinatorial libraries that addresses many of the problems encountered when using conventional instruments. For example, the disclosed instruments can measure mechanical properties of library members in rapid serial or parallel test format, and can perform tests on small amounts of material, which are easily prepared or dispensed using art-disclosed liquid or solid handling techniques. Compared to conventional instruments, the disclosed instruments afford faster sample loading and unloading, for example, through the use of disposable libraries of material samples.

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